Notice of References Cited 10/053,876 Reexamination O,DELL ET AL. Examiner Amir Alavi Reexamination O,DELL ET AL. Page 1 of 1

Application/Control No.

U.S. PATENT DOCUMENT	U.S. F	ATENT	DOCU	MEN	ITS
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α.	US-4,379,288	04-1983	Leung et al.	341/28
*	В	US-4,505,602	03-1985	Wong, Wyman S.	400/110
*	C	US-5,790,055	08-1998	Yu, Cho Jen	341/28
*	D	US-5,831,636	11-1998	Merchant et al.	345/467
*	E	US-5,586,198	12-1996	Lakritz, David	382/185
*	F	US-5,475,767	12-1995	Du, Bingchan	382/185
*	G	US-5,410,306	04-1995	Ye, Liana X.	341/28
*	Н	US-5,257,938	11-1993	Tien, Hsin C.	434/128
*	ı	US-5,109,352	04-1992	O'Dell, Robert B.	715/542
*	j	US-5,223,831	06-1993	Kung et al.	340/7.56
*	К	US-5,212,769	05-1993	Pong, Gim	345/467
*	L	US-4,879,653	11-1989	Shinoto, Yoshinori	715/535
	М	US-		·	

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	V	
	>	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Applicant(s)/Patent Under